
Quartz crystal controlled oscillators of assessed quality - Part 1: Generic specification (IEC 60679-1:1997/A1:2002)

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[SIST EN 60679-1:2002/A1:2003](https://standards.iteh.ai/catalog/standards/sist/08835cc0-c98b-4179-81d0-2fb058dec069/sist-en-60679-1-2002-a1-2003)

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EUROPEAN STANDARD

EN 60679-1/A1

NORME EUROPÉENNE

EUROPÄISCHE NORM

March 2002

ICS 31.140

English version

**Quartz crystal controlled oscillators of assessed quality
Part 1: Generic specification
(IEC 60679-1:1997/A1:2002)**

Oscillateurs pilotés par quartz
sous assurance de la qualité
Partie 1: Spécification générique
(CEI 60679-1:1997/A1:2002)

Quarzoszillatoren mit bewerteter Qualität
Teil 1: Fachgrundspezifikation
(IEC 60679-1:1997/A1:2002)

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This amendment A1 modifies the European Standard EN 60679-1:1998; it was approved by CENELEC on 2002-03-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this amendment the status of a national standard without any alteration. <https://standards.iteh.ai/catalog/standards/sist/08835cc0-c98b-4179-81d0-2fb058dec069/sist-en-60679-1-2002-a1-2002>

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This amendment exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Malta, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 49/523/FDIS, future amendment 1 to IEC 60679-1:1997, prepared by IEC TC 49, Piezoelectric and dielectric devices for frequency control and selection, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as amendment A1 to EN 60679-1:1998 on 2002-03-01.

The following dates were fixed:

- latest date by which the amendment has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2002-12-01
- latest date by which the national standards conflicting with the amendment have to be withdrawn (dow) 2005-03-01

Annexes designated "normative" are part of the body of the standard.
In this standard, annexes A, B, C and ZA are normative.
Annex ZA has been added by CENELEC.

Endorsement notice

The text of amendment 1:2002 to the International Standard IEC 60679-1:1997 was approved by CENELEC as an amendment to the European Standard without any modification.

[SIST EN 60679-1:2002/A1:2003](https://standards.iteh.ai/catalog/standards/sist/08835cc0-c98b-4179-81d0-2fb058dec069/sist-en-60679-1-2002-a1-2003)

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Annex ZA
(normative)

**Normative references to international publications
with their corresponding European publications**

Add:

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60748-2	1997	Semiconductor devices - Integrated circuits Part 2: Digital integrated circuits	-	-
IEC/PAS 62179	- 1)	Electrostatic discharge (ESD) sensitivity testing human body model (HBM)	-	-
IEC/PAS 62180	- 1)	Electrostatic discharge (ESD) sensitivity testing machine model (MM)	-	-

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1) Undated reference.

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NORME
INTERNATIONALE
INTERNATIONAL
STANDARD

CEI
IEC
60679-1

1997

AMENDEMENT 1
AMENDMENT 1
2002-01

Amendement 1

Oscillateurs pilotés par quartz
sous assurance de la qualité –

Partie 1:
Spécification générique

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Amendement 1

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Quartz crystal controlled oscillators
of assessed quality –

Part 1:
Generic specification

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Commission Electrotechnique Internationale
International Electrotechnical Commission
Международная Электротехническая Комиссия

CODE PRIX
PRICE CODE

E

Pour prix, voir catalogue en vigueur
For price, see current catalogue

FOREWORD

This amendment has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

The text of this amendment is based on the following documents:

FDIS	Report on voting
49/523/FDIS	49/531/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

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CONTENTS

Replace the titles of the annexes by the following:

Annex A Load circuit for logic drive

Annex B Latch-up test

Annex C Electrostatic discharge sensitivity classification

Bibliography

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FOREWORD

Replace, on page 11, the sentence 'Annex A forms an integral part of this standard' by the following:

Annexes A, B and C form an integral part of this standard.

Delete, on page 11, the sentence 'Annex B is for information only'.

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1.2 Normative references

Insert, on page 15, the following new standards:

IEC 60748-2:1997, *Semiconductor devices – Integrated circuits – Part 2: Digital integrated circuits*

IEC/PAS 62179, *Electrostatic discharge (ESD) sensitivity testing human body model (HBM)*

IEC/PAS 62180, *Electrostatic discharge (ESD) sensitivity testing machine model (MM)*

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Insert, after annex A, the new annexes B and C.

Annex B (normative)

Latch-up test

B.1 Definition

B.1.1 Latch-up

A state in which a low-impedance path results from (and persists following) an input, output or supply overvoltage.

B.1.2 Test procedure

The latch-up test under static conditions subjects a device to greater stresses than it would encounter in normal operation and is even more severe than dynamic test methods using similar levels of current and voltage.

This test, if performed according to the procedures defined in this standard, is a necessary and sufficient method for the characterization of the latch-up susceptibility or immunity of quartz crystal controlled oscillators incorporating CMOS integrated circuits.

B.2 Test method

B.2.1 This test is destructive. <http://standards.iteh.ai/catalog/standards/sist/08835cc0-c98b-4179-81d0-2fb058dec069/sist-en-60679-1-2002-a1-2003>

B.2.2 This test is applicable only to quartz crystal controlled oscillators containing CMOS integrated circuits.

B.2.3 This test shall be performed in accordance with IEC 60748-2.

B.2.4 This test is a recommended test procedure. It is not a specification. No test limits are given.

B.2.5 This test is performed for characterization and inspection purposes only. It is not a production test.